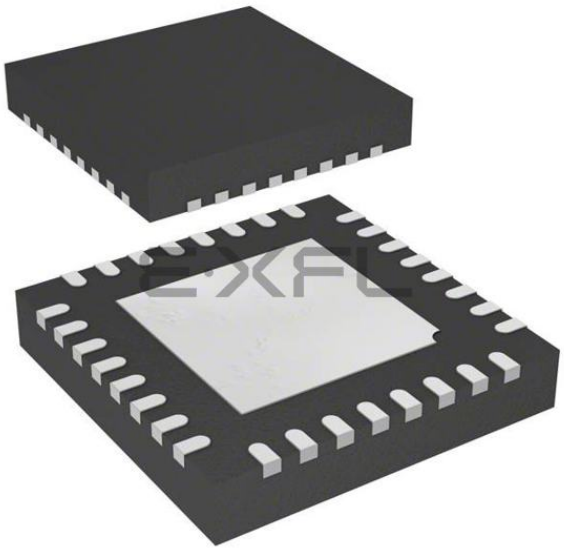

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, POR, PWM, WDT
Number of I/O	30
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-UFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l151k4u6

3.17 Communication interfaces

3.17.1 SPI

The serial peripheral interface (SPI1) provides half/ full duplex synchronous serial communication with external devices.

- Maximum speed: 8 Mbit/s (f_{SYSCLK}/2) both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on 2 lines with a possible bidirectional data line
- Master or slave operation - selectable by hardware or software
- Hardware CRC calculation
- Slave/master selection input pin

Note: SPI1 can be served by the DMA1 Controller.

3.17.2 I²C

The I^2C bus interface (I^2C1) provides multi-master capability, and controls all I²C bus-specific sequencing, protocol, arbitration and timing.

- Master, slave and multi-master capability
- Standard mode up to 100 kHz and fast speed modes up to 400 kHz.
- 7-bit and 10-bit addressing modes.
- SMBus 2.0 and PMBus support
- Hardware CRC calculation

Note: I^2C1 can be served by the DMA1 Controller.

3.17.3 USART

The USART interface (USART1) allows full duplex, asynchronous communications with external devices requiring an industry standard NRZ asynchronous serial data format. It offers a very wide range of baud rates.

- 1 Mbit/s full duplex SCI
- SPI1 emulation
- High precision baud rate generator
- SmartCard emulation
- IrDA SIR encoder decoder
- Single wire half duplex mode

Note: USART1 can be served by the DMA1 Controller.

3.18 Infrared (IR) interface

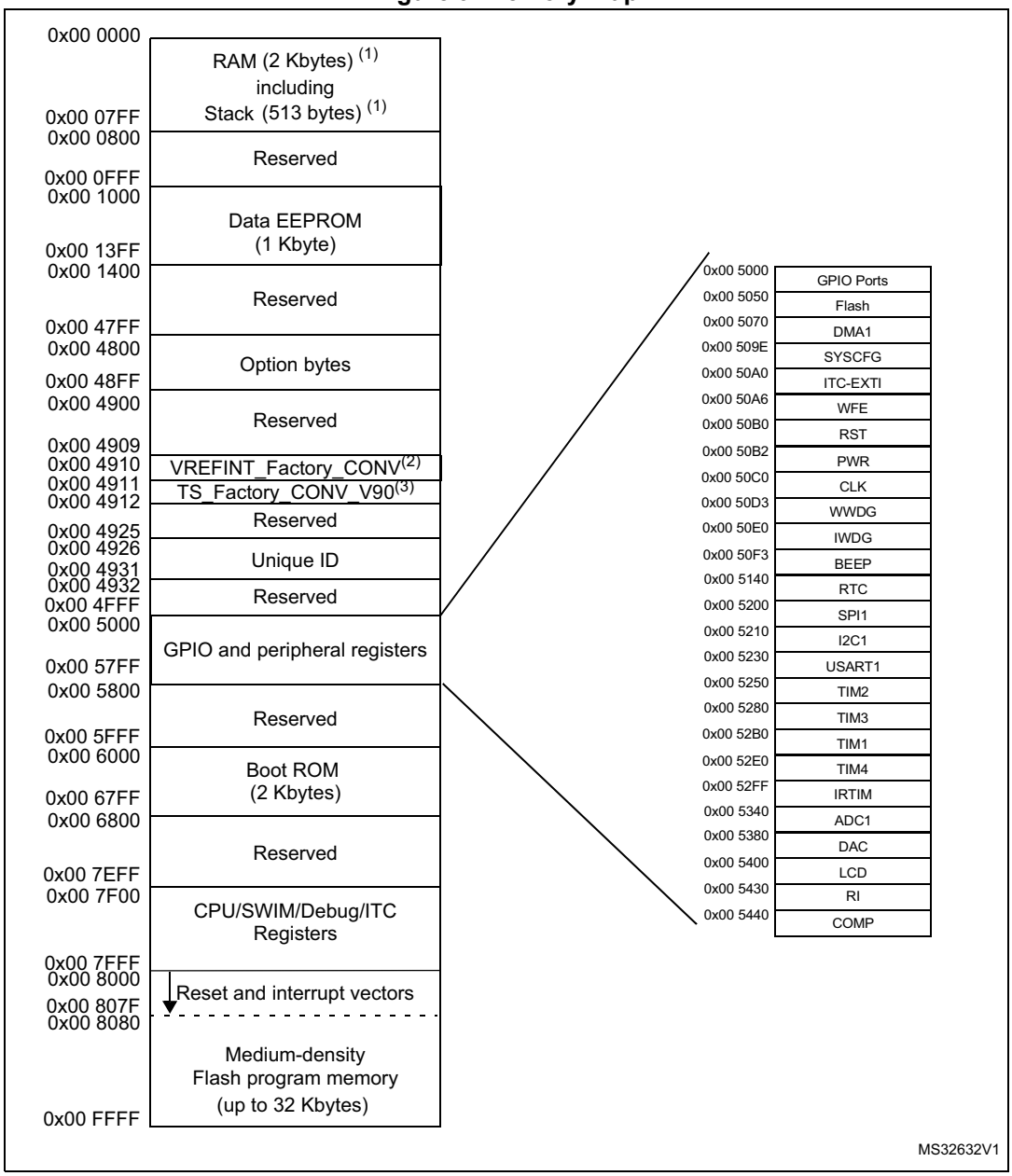
The medium-density STM8L151x4/6 and STM8L152x4/6 devices contain an infrared interface which can be used with an IR LED for remote control functions. Two timer output compare channels are used to generate the infrared remote control signals.

5 Memory and register map

5.1 Memory mapping

The memory map is shown in *Figure 9*.

Figure 9. Memory map



1. *Table 6* lists the boundary addresses for each memory size. The top of the stack is at the RAM end address.
2. The VREFINT_Factory_CONV byte represents the LSB of the V_{REFINT} 12-bit ADC conversion result. The MSB have a fixed value: 0x6.
3. The TS_Factory_CONV_V90 byte represents the LSB of the V_{90} 12-bit ADC conversion result. The MSB

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5200	SPI1	SPI1_CR1	SPI1 control register 1	0x00
0x00 5201		SPI1_CR2	SPI1 control register 2	0x00
0x00 5202		SPI1_ICR	SPI1 interrupt control register	0x00
0x00 5203		SPI1_SR	SPI1 status register	0x02
0x00 5204		SPI1_DR	SPI1 data register	0x00
0x00 5205		SPI1_CRCPR	SPI1 CRC polynomial register	0x07
0x00 5206		SPI1_RXCRCR	SPI1 Rx CRC register	0x00
0x00 5207		SPI1_TXCRCR	SPI1 Tx CRC register	0x00
0x00 5208 to 0x00 520F	Reserved area (8 bytes)			
0x00 5210	I2C1	I2C1_CR1	I2C1 control register 1	0x00
0x00 5211		I2C1_CR2	I2C1 control register 2	0x00
0x00 5212		I2C1_FREQR	I2C1 frequency register	0x00
0x00 5213		I2C1_OARL	I2C1 own address register low	0x00
0x00 5214		I2C1_OARH	I2C1 own address register high	0x00
0x00 5215		Reserved (1 byte)		
0x00 5216		I2C1_DR	I2C1 data register	0x00
0x00 5217		I2C1_SR1	I2C1 status register 1	0x00
0x00 5218		I2C1_SR2	I2C1 status register 2	0x00
0x00 5219		I2C1_SR3	I2C1 status register 3	0x0x
0x00 521A		I2C1_ITR	I2C1 interrupt control register	0x00
0x00 521B		I2C1_CCRL	I2C1 clock control register low	0x00
0x00 521C		I2C1_CCRH	I2C1 clock control register high	0x00
0x00 521D		I2C1_TRISER	I2C1 TRISE register	0x02
0x00 521E		I2C1_PECR	I2C1 packet error checking register	0x00
0x00 521F to 0x00 522F	Reserved area (17 bytes)			

Table 11. Interrupt mapping (continued)

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode)(1)	Vector address
19	TIM2	TIM2 update/overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 8054
20	TIM2	TIM2 capture/ compare interrupt	-	-	Yes	Yes	0x00 8058
21	TIM3	TIM3 update/overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 805C
22	TIM3	TIM3 capture/ compare interrupt	-	-	Yes	Yes	0x00 8060
23	TIM1	Update /overflow/trigger/ COM	-	-	-	Yes	0x00 8064
24	TIM1	Capture/compare	-	-	-	Yes	0x00 8068
25	TIM4	TIM4 update/overflow/ trigger interrupt	-	-	Yes	Yes	0x00 806C
26	SPI1	SPI1 TX buffer empty/ RX buffer not empty/ error/wakeup interrupt	Yes	Yes	Yes	Yes	0x00 8070
27	USART1	USART1 transmit data register empty/ transmission complete interrupt	-	-	Yes	Yes	0x00 8074
28	USART1	USART1 received data ready/overrun error/ idle line detected/parity error/global error interrupt	-	-	Yes	Yes	0x00 8078
29	I^2C1	I^2C1 interrupt(3)	Yes	Yes	Yes	Yes	0x00 807C

1. The Low power wait mode is entered when executing a WFE instruction in Low power run mode. In WFE mode, the interrupt is served if it has been previously enabled. After processing the interrupt, the processor goes back to WFE mode. When the interrupt is configured as a wakeup event, the CPU wakes up and resumes processing.
2. The interrupt from PVD is logically OR-ed with Port E and F interrupts. Register EXTI_CONF allows to select between Port E and Port F interrupt (see *External interrupt port select register (EXTI_CONF)* in the RM0031).
3. The device is woken up from Halt or Active-halt mode only when the address received matches the interface address.

8 Unique ID

STM8 devices feature a 96-bit unique device identifier which provides a reference number that is unique for any device and in any context. The 96 bits of the identifier can never be altered by the user.

The unique device identifier can be read in single bytes and may then be concatenated using a custom algorithm.

The unique device identifier is ideally suited:

- For use as serial numbers
- For use as security keys to increase the code security in the program memory while using and combining this unique ID with software cryptographic primitives and protocols before programming the internal memory.
- To activate secure boot processes

Table 14. Unique ID registers (96 bits)

Address	Content description	Unique ID bits							
		7	6	5	4	3	2	1	0
0x4926	X co-ordinate on the wafer	U_ID[7:0]							
0x4927		U_ID[15:8]							
0x4928	Y co-ordinate on the wafer	U_ID[23:16]							
0x4929		U_ID[31:24]							
0x492A	Wafer number	U_ID[39:32]							
0x492B	Lot number	U_ID[47:40]							
0x492C		U_ID[55:48]							
0x492D		U_ID[63:56]							
0x492E		U_ID[71:64]							
0x492F		U_ID[79:72]							
0x4930		U_ID[87:80]							
0x4931		U_ID[95:88]							

Table 16. Current characteristics

Symbol	Ratings	Max.	Unit
I_{VDD}	Total current into V_{DD} power line (source)	80	mA
I_{VSS}	Total current out of V_{SS} ground line (sink)	80	
I_{IO}	Output current sunk by IR_TIM pin (with high sink LED driver capability)	80	
	Output current sunk by any other I/O and control pin	25	
	Output current sourced by any I/Os and control pin	- 25	
$I_{INJ(PIN)}$	Injected current on true open-drain pins (PC0 and PC1)(1)	- 5 / +0	mA
	Injected current on five-volt tolerant (FT) pins (PA7 and PE0) (1)	- 5 / +0	
	Injected current on 3.6 V tolerant (TT) pins (1)	- 5 / +0	
	Injected current on any other pin (2)	- 5 / +5	
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/O and control pins) (3)	± 25	

1. Positive injection is not possible on these I/Os. A negative injection is induced by $V_{IN}<V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to *Table 15.* for maximum allowed input voltage values.
2. A positive injection is induced by $V_{IN}>V_{DD}$ while a negative injection is induced by $V_{IN}<V_{SS}$. $I_{INJ(PIN)}$ must never be exceeded. Refer to *Table 15.* for maximum allowed input voltage values.
3. When several inputs are submitted to a current injection, the maximum $\Sigma I_{INJ(PIN)}$ is the absolute sum of the positive and negative injected currents (instantaneous values).

Table 17. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	-65 to +150	° C
T_J	Maximum junction temperature	150	

9.3 Operating conditions

Subject to general operating conditions for V_{DD} and T_A.

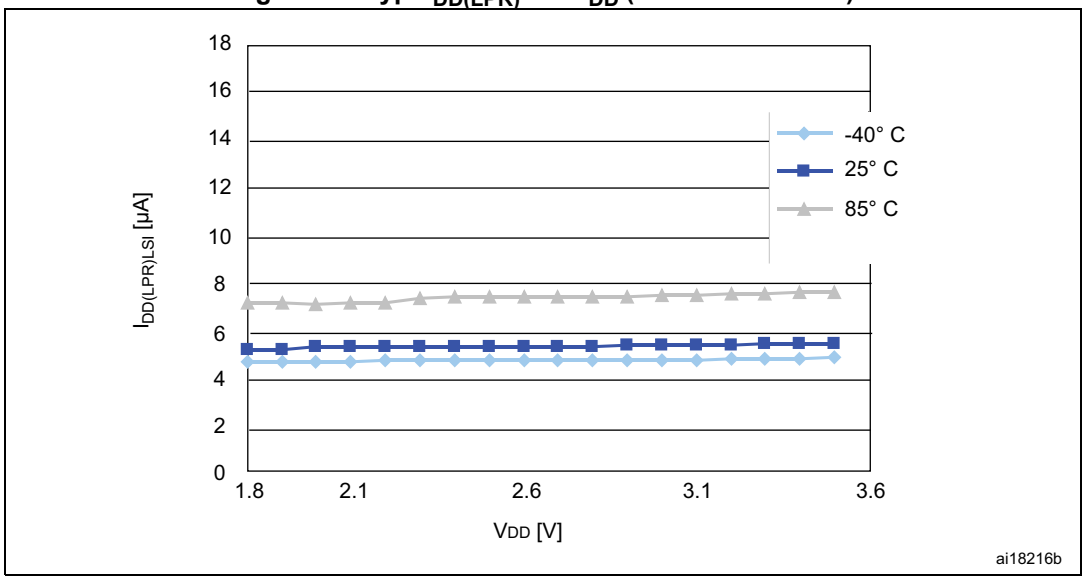
9.3.1 General operating conditions

Table 18. General operating conditions

Symbol	Parameter	Conditions		Min.	Max.	Unit
f_{SYSCLK}(1)	System clock frequency	1.65 V ≤V_{DD} < 3.6 V		0	16	MHz
V_{DD}	Standard operating voltage	-		1.65(2)	3.6	V
V_{DDA}	Analog operating voltage	ADC and DAC not used	Must be at the same potential as V_{DD}	1.65(2)	3.6	V
		ADC or DAC used		1.8	3.6	V
P_D(3)	Power dissipation at T_A= 85 °C for suffix 6 devices	LQFP48		-	288	mW
		UFQFPN48		-	169	
		LQFP32		-	288	
		UFQFPN32		-	169	
		UFQFPN28		-	169	
		WLCSP28		-	286	
	Power dissipation at T_A= 125 °C for suffix 3 devices and at T_A= 105 °C for suffix 7 devices	LQFP48		-	77	
		UFQFPN48		-	156	
		LQFP32		-	85	
		UFQFPN32		-	131	
		UFQFPN28		-	42	
		WLCSP28		-	71	
T_A	Temperature range	1.65 V ≤V_{DD} < 3.6 V (6 suffix version)		-40	85	°C
		1.65 V ≤V_{DD} < 3.6 V (7 suffix version)		-40	105	
		1.65 V ≤V_{DD} < 3.6 V (3 suffix version)		-40	125	
T_J	Junction temperature range	-40 °C ≤T_A < 85 °C (6 suffix version)		-40	105(4)	°C
		-40 °C ≤ T_A < 105 °C (7 suffix version)		-40	110(4)	
		-40 °C ≤ T_A < 125 °C (3 suffix version)		-40	130	

1. f_{SYSCLK} = f_{CPU}
2. 1.8 V at power-up, 1.65 V at power-down if BOR is disabled
3. To calculate $P_{Dmax}(T_A)$, use the formula $P_{Dmax}=(T_{Jmax} - T_A)/\Theta_{JA}$ with T_{Jmax} in this table and Θ_{JA} in “Thermal characteristics” table.
4. T_{Jmax} is given by the test limit. Above this value the product behavior is not guaranteed.

Figure 15. Typ. $I_{DD(LPR)}$ vs. V_{DD} (LSI clock source)



In the following table, data is based on characterization results, unless otherwise specified.

Table 24. Total current consumption and timing in Active-halt mode at V_{DD} = 1.65 V to 3.6 V

Symbol	Parameter	Conditions (1)			Typ	Max	Unit
$I_{DD(AH)}$	Supply current in Active-halt mode	LSI RC (at 38 kHz)	LCD OFF(2)	T_A = -40 °C to 25 °C	0.9	2.1	µA
				T_A = 55 °C	1.2	3	
				T_A = 85 °C	1.5	3.4	
				T_A = 105 °C	2.6	6.6	
				T_A = 125 °C	5.1	12	
			LCD ON (static duty/ external V_{LCD}) (3)	T_A = -40 °C to 25 °C	1.4	3.1	
				T_A = 55 °C	1.5	3.3	
				T_A = 85 °C	1.9	4.3	
				T_A = 105 °C	2.9	6.8	
				T_A = 125 °C	5.5	13	
			LCD ON (1/4 duty/ external V_{LCD}) (4)	T_A = -40 °C to 25 °C	1.9	4.3	
				T_A = 55 °C	1.95	4.4	
				T_A = 85 °C	2.4	5.4	
				T_A = 105 °C	3.4	7.6	
				T_A = 125 °C	6.0	15	
			LCD ON (1/4 duty/ internal V_{LCD}) (5)	T_A = -40 °C to 25 °C	3.9	8.75	
				T_A = 55 °C	4.15	9.3	
				T_A = 85 °C	4.5	10.2	
				T_A = 105 °C	5.6	13.5	
				T_A = 125 °C	6.8	16.3	

9.3.8 Communication interfaces

SPI1 - Serial peripheral interface

Unless otherwise specified, the parameters given in *Table 43* are derived from tests performed under ambient temperature, f_{SYSCLK} frequency and V_{DD} supply voltage conditions summarized in *Section 9.3.1*. Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 43. SPI1 characteristics

Symbol	Parameter	Conditions(1)	Min	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI1 clock frequency	Master mode	0	8	MHz
		Slave mode	0	8	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI1 clock rise and fall time	Capacitive load: C = 30 pF	-	30	ns
$t_{su(NSS)}$(2)	NSS setup time	Slave mode	4 x $1/f_{SYSCLK}$	-	
$t_{h(NSS)}$(2)	NSS hold time	Slave mode	80	-	
$t_{w(SCKH)}$(2) $t_{w(SCKL)}$(2)	SCK high and low time	Master mode, f_{MASTER} = 8 MHz, f_{SCK}= 4 MHz	105	145	
$t_{su(MI)}$(2) $t_{su(SI)}$(2)	Data input setup time	Master mode	30	-	
		Slave mode	3	-	
$t_{h(MI)}$(2) $t_{h(SI)}$(2)	Data input hold time	Master mode	15	-	
		Slave mode	0	-	
$t_{a(SO)}$(2)(3)	Data output access time	Slave mode	-	3x $1/f_{SYSCLK}$	
$t_{dis(SO)}$(2)(4)	Data output disable time	Slave mode	30	-	
$t_{v(SO)}$(2)	Data output valid time	Slave mode (after enable edge)	-	60	
$t_{v(MO)}$(2)	Data output valid time	Master mode (after enable edge)	-	20	
$t_{h(SO)}$(2)	Data output hold time	Slave mode (after enable edge)	15	-	
$t_{h(MO)}$(2)		Master mode (after enable edge)	1	-	

1. Parameters are given by selecting 10 MHz I/O output frequency.
2. Values based on design simulation and/or characterization results.
3. Min time is for the minimum time to drive the output and max time is for the maximum time to validate the data.
4. Min time is for the minimum time to invalidate the output and max time is for the maximum time to put the data in Hi-Z.

9.3.11 Temperature sensor

In the following table, data is based on characterization results, not tested in production, unless otherwise specified.

Table 47. TS characteristics

Symbol	Parameter	Min	Typ	Max.	Unit
V_{90}(1)	Sensor reference voltage at 90°C ±5 °C,	0.580	0.597	0.614	V
T_L	V_{SENSOR} linearity with temperature	-	±1	±2	°C
Avg_slope (2)	Average slope	1.59	1.62	1.65	mV/°C
$I_{DD(TEMP)}$(2)	Consumption	-	3.4	6	µA
T_{START}(2)(3)	Temperature sensor startup time	-	-	10	µs
T_{S_TEMP}(2)	ADC sampling time when reading the temperature sensor	10	-	-	µs

1. Tested in production at V_{DD} = 3 V ±10 mV. The 8 LSB of the V_{90} ADC conversion result are stored in the TS_Factory_CONV_V90 byte.
2. Data guaranteed by design.
3. Defined for ADC output reaching its final value ±1/2LSB.

9.3.12 Comparator characteristics

In the following table, data is guaranteed by design, not tested in production, unless otherwise specified.

Table 48. Comparator 1 characteristics

Symbol	Parameter	Min	Typ	Max(1)	Unit
V_{DDA}	Analog supply voltage	1.65	-	3.6	V
T_A	Temperature range	-40	-	125	°C
R_{400K}	R_{400K} value	300	400	500	kΩ
R_{10K}	R_{10K} value	7.5	10	12.5	
V_{IN}	Comparator 1 input voltage range	0.6	-	V_{DDA}	V
V_{REFINT}	Internal reference voltage(2)	1.202	1.224	1.242	
t_{START}	Comparator startup time	-	7	10	µs
t_d	Propagation delay(3)	-	3	10	
V_{offset}	Comparator offset error	-	±3	±10	mV
I_{COMP1}	Current consumption(4)	-	160	260	nA

1. Based on characterization.
2. Tested in production at V_{DD} = 3 V ±10 mV.
3. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
4. Comparator consumption only. Internal reference voltage not included.

9.3.13 12-bit DAC characteristics

In the following table, data is guaranteed by design, not tested in production.

Table 50. DAC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	-	1.8	-	V_{DDA}	
I_{VREF}	Current consumption on V_{REF+} supply	V_{REF+} = 3.3 V, no load, middle code (0x800)	-	130	220	µA
		V_{REF+} = 3.3 V, no load, worst code (0x000)	-	220	350	
I_{VDDA}	Current consumption on V_{DDA} supply	V_{DDA} = 3.3 V, no load, middle code (0x800)	-	210	320	
		V_{DDA} = 3.3 V, no load, worst code (0x000)	-	320	520	
T_A	Temperature range	-	-40	-	125	°C
R_L	Resistive load(1) (2)	DACOUT buffer ON	5	-	-	kΩ
R_O	Output impedance	DACOUT buffer OFF	-	8	10	kΩ
C_L	Capacitive load(3)	-	-	-	50	pF
DAC_OUT	DAC_OUT voltage(4)	DACOUT buffer ON	0.2	-	V_{DDA}-0.2	V
		DACOUT buffer OFF	0	-	V_{REF+} -1 LSB	V
$t_{settling}$	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches the final value ±1LSB)	R_L ≥5 kΩ, C_L≤ 50 pF	-	7	12	µs
Update rate	Max frequency for a correct DAC_OUT (@95%) change when small variation of the input code (from code i to i+1LSB).	R_L ≥ 5 kΩ, C_L ≤50 pF	-		1	Msps
t_{WAKEUP}	Wakeup time from OFF state. Input code between lowest and highest possible codes.	R_L ≥5 kΩ, C_L≤50 pF	-	9	15	µs
PSRR+	Power supply rejection ratio (to V_{DDA}) (static DC measurement)	R_L≥ 5 kΩ, C_L≤50 pF	-	-60	-35	dB

1. Resistive load between DACOUT and GNDA.
2. Output on PF0 (48-pin package only).
3. Capacitive load at DACOUT pin.
4. It gives the output excursion of the DAC.

Table 59. EMI data (1)

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. 16 MHz	Unit
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = +25 °C, LQFP32 conforming to IEC61967-2	0.1 MHz to 30 MHz	-3	dBµV
			30 MHz to 130 MHz	9	
			130 MHz to 1 GHz	4	
			SAE EMI Level	2	-

1. Not tested in production.

Absolute maximum ratings (electrical sensitivity)

Based on two different tests (ESD and LU) using specific measurement methods, the product is stressed in order to determine its performance in terms of electrical sensitivity. For more details, refer to the application note AN1181.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts*(n+1) supply pin). Two models can be simulated: human body model and charge device model. This test conforms to the JESD22-A114A/A115A standard.

Table 60. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Maximum value (1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)		500	

1. Data based on characterization results.

Static latch-up

- **LU**: 3 complementary static tests are required on 6 parts to assess the latch-up performance. A supply overvoltage (applied to each power supply pin) and a current injection (applied to each input, output and configurable I/O pin) are performed on each sample. This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

Table 61. Electrical sensitivities

Symbol	Parameter	Class
LU	Static latch-up class	II

Table 62. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data

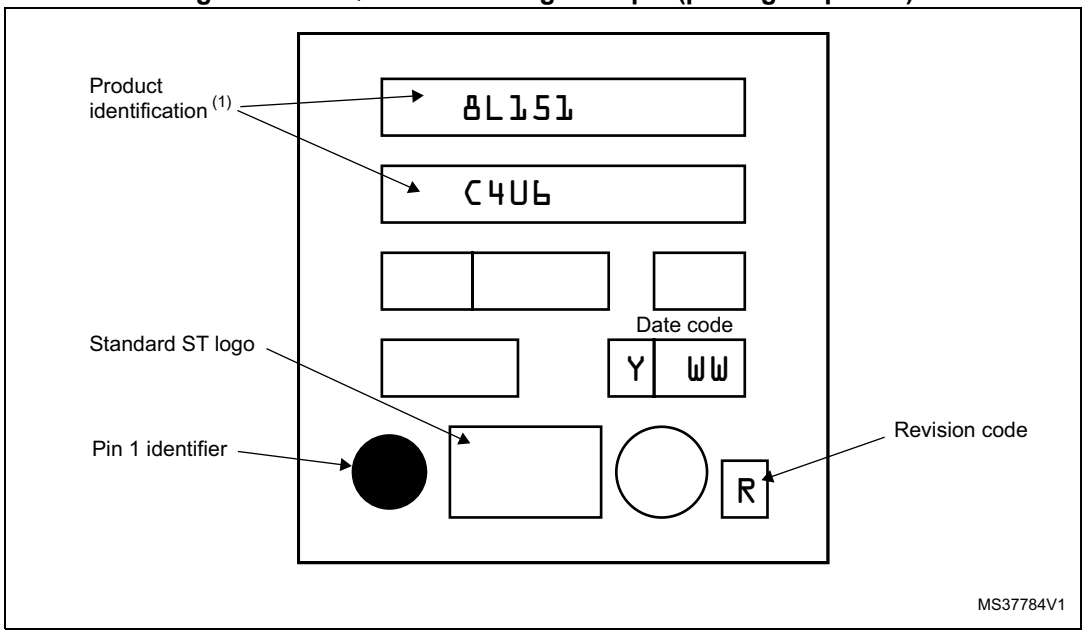
Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location. Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

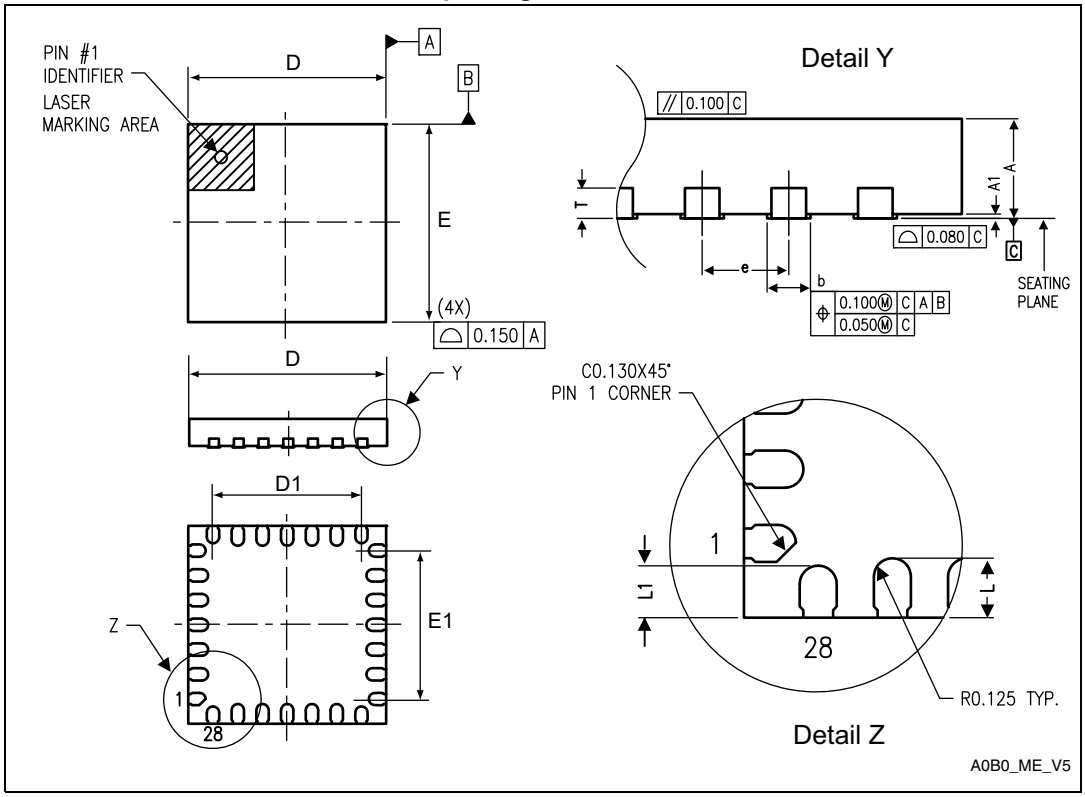
Figure 48. UFQFPN48 marking example (package top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

10.6 UFQFPN28 package information

Figure 55. UFQFPN28 - 28-lead, 4 x 4 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package outline



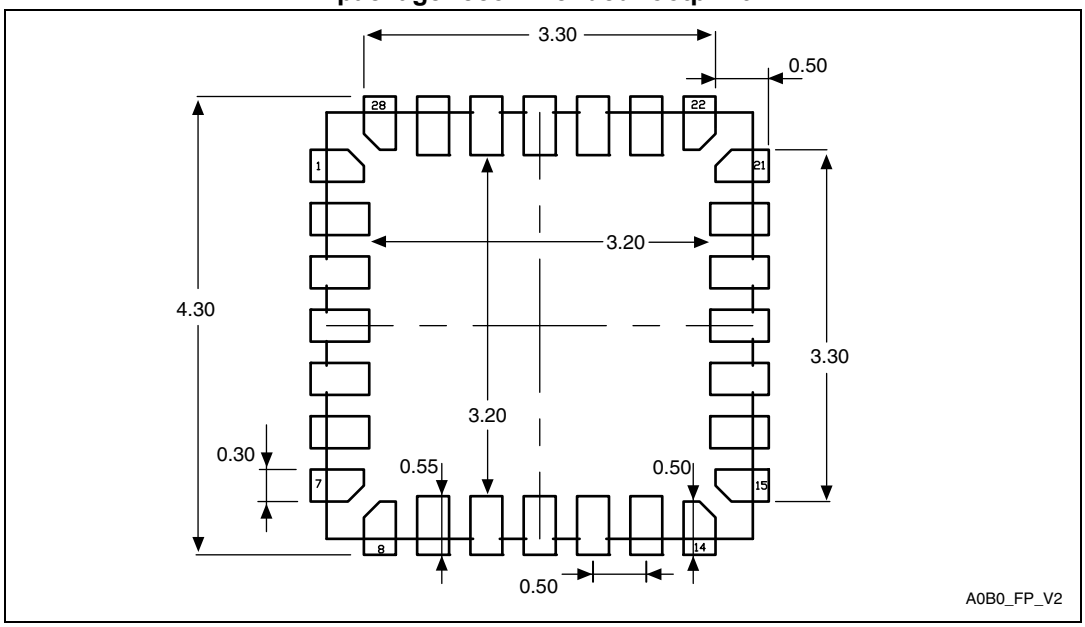
1. Drawing is not to scale.

Table 66. UFQFPN28 - 28-lead, 4 x 4 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package mechanical data(1)

Symbol	millimeters			inches		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	-	0.000	0.050	-	0.0000	0.0020
D	3.900	4.000	4.100	0.1535	0.1575	0.1614
D1	2.900	3.000	3.100	0.1142	0.1181	0.1220
E	3.900	4.000	4.100	0.1535	0.1575	0.1614
E1	2.900	3.000	3.100	0.1142	0.1181	0.1220
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
L1	0.250	0.350	0.450	0.0098	0.0138	0.0177
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 56. UFQFPN28 - 28-lead, 4 x 4 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

Table 67. WLCSP28 - 28-pin, 1.703 x 2.841 mm, 0.4 mm pitch wafer level chip scale package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	0.540	0.570	0.600	0.0213	0.0224	0.0236
A1	-	0.190	-	-	0.0075	-
A2	-	0.380	-	-	0.0150	-
b[2]	0.240	0.270	0.300	0.0094	0.0106	0.0118
D	1.668	1.703	1.738	0.0657	0.0670	0.0684
E	2.806	2.841	2.876	0.1105	0.1119	0.1132
e	-	0.400	-	-	0.0157	-
e1	-	1.200	-	-	0.0472	-
e2	-	2.400	-	-	0.0945	-
F	-	0.251	-	-	0.0099	-
G	-	0.222	-	-	0.0087	-
aaa	-	-	0.100	-	-	0.0039
bbb	-	-	0.100	-	-	0.0039
ccc	-	-	0.100	-	-	0.0039
ddd	-	-	0.050	-	-	0.0020
eee	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.
2. Dimension is measured at the maximum bump diameter parallel to primary datum Z.

Device marking

The following figure gives an example of topside marking orientation versus ball A1 identifier location. Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Table 69. Document revision history (continued)

Date	Revision	Changes
23-Jul-2010	5	Modified *Introduction* and *Description.* Modified *Table: Legend/abbreviation for table 5* and *Table: Medium density STM8L15x pin description* (for PA0, PA1, PB0 and PB4 and for reset states in the floating input column) Modified *Figure: Low density STM8L151xx device block diagram, Figure: Low density STM8L15x clock tree diagram*, *Figure: Low power modes* and *Figure : Low power real-time clock.* Modified CLK_PCKENR2 and CLK_HSICALR reset values in *Table: General hardware register map.* Modified notes below *Figure: Memory map.* Modified PA_CR1 reset value. Modified reset values for Px_IDR registers. Modified *Table: Voltage characteristics* and *Table: Current characteristics.* Modified V_{IH} in *Table: I/O static characteristics.* Modified *Table: Total current consumption in Wait mode.* Modified *Figure Typical application with I2C bus and timing diagram 1).* Modified I_L value in *Figure: Typical connection diagram using the ADC1.* Modified R_H and R_L in *Table: LCD characteristics.* Added graphs in *Section: Electrical parameters.* Modified note 3 below *Table: Reference voltage characteristics.* Modified note 1 below *Table: TS characteristics.* Changed $V_{ESD(CDM)}$ value in *Table: ESD absolute maximum ratings.* Updated notes for UFQFPN32 and UFQFPN48 packages.
11-Mar-2011	6	Modified note on true open drain I/Os and I/O level columns in *Table: Medium density STM8L15x pin description.* Remapping option removed for USART1_TX, USART1_RX, and USART1_CK on PC2, PC3 and PC4 in *Table: Medium density STM8L15x pin description.* Modified IDWDG_KR reset value in *Table: General hardware register map.* Replaced VREF_OUT with VREFINT and TIMx_TRIG with TIMx_ETR. Added *Table: Factory conversion registers.* Modified reset values for TIM1_DCR1, IWDG_KR, RTC_DR1, RTC_DR2, RTC_SPRERH, RTC_SPRERL, RTC_APRER, RTC_WUTRH, and RTC_WUTRL in *Table: General hardware register map.* Added notes to certain values in *Section: Embedded reference voltage* and *Section: Temperature sensor.*